

MOSFET - N-Channel, QFET®

1000 V, 1.6 A, 9 Ω

FQU2N100, FQD2N100

This N-Channel enhancement mode power MOSFET is produced using **onsemi**'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

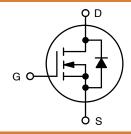
- 1.6 A, 1000 V, $R_{DS(on)} = 9 \Omega$ (Max.) @ $V_{GS} = 10 \text{ V}$, $I_D = 0.8 \text{ A}$
- Low Gate Charge (Typ. 12 nC)
- Low Crss (Typ. 5 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free, Halide Free and are RoHS Compliant

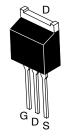
MAXIMUM RATINGS (T_C = 25 °C unless otherwise noted)

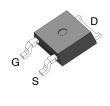
Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	1000	V
Drain Current - Continuous (T _C = 25 °C) - Continuous (T _C = 100 °C)	I _D	1.6 1.0	Α
Drain Current - Pulsed (Note 2)	I _{DM}	6.4	Α
Gate-Source Voltage	V _{GSS}	±30	V
Single Pulsed Avalanche Energy (Note 3)	E _{AS}	160	mJ
Avalanche Current (Note 2)	I _{AR}	1.6	Α
Repetitive Avalanche Energy (Note 2)	E _{AR}	5.0	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	5.5	V/ns
Power Dissipation (T _A = 25 °C) *	P _D	2.5	W
Power Dissipation (T _C = 25 °C) - Derate above 25 °C		50 0.4	W W/°C
Operating and Storage Temperature Range	T _J , T _{STG}	–55 to +150	°C
Maximum Lead Temperature for Soldering Purposes, 1/8" (from case for 5 seconds)	T_L	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

V _{DSS}	R _{DS(ON)} MAX	I _D MAX
1000 V	9 Ω @ 10 V	1.6 A



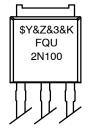




DPAK3 (IPAK) CASE 369AR

DPAK3 (TO-252 3 LD) CASE 369AS

MARKING DIAGRAMS





FQU2N100,

FQD2N100 = Device Code \$Y = onsemi Logo &Z = Assembly Location &3 = 3-Digit Date Code

&K = 2-Digits Lot Run Traceability Code

ORDERING INFORMATION

Device	Package	Shipping [†]
FQD2N100TM	DPAK3 (Pb-Free)	2500 / Tape & Reel

DISCONTINUED (Note 1)

FQU2N100TU	DPAK3 (IPAK)	70 Units / Tube
	(Pb-Free)	

- † For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, <u>BRD8011/D</u>.
- DISCONTINUED: This device is not available. Please contact your onsemi representative for information. The most current information on this device may be available on www.onsemi.com.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (minimum pad of 2 oz copper) , Max.	110	°C/W
	Thermal Resistance, Junction-to-Ambient (* 1 in2 pad of 2 oz copper), Max.	50	

ELECTRICAL CHARACTERISTICS /T

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	ACTERISTICS	•	•			
BV _{DSS}	Drain-to-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	1000	-	_	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25 °C	-	0.97 6	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 1000 V, V _{GS} = 0 V	_	-	10	μΑ
		V _{DS} = 800 V, T _C = 125 °C	-	-	100	
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V	-	-	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V	_	-	-100	nA
ON CHARA	CTERISTICS	•				
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain-Source On Resistance	V _{GS} = 10 V, I _D = 0.8 A	_	7.1	9	Ω
9FS	Forward Transconductance	V _{DS} = 50 V, I _D = 0.8 A	_	1.9	_	S
DYNAMIC C	HARACTERISTICS					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz	_	400	520	pF
C _{oss}	Output Capacitance		-	40	52	
C _{rss}	Reverse Transfer Capacitance		-	5	6.5	
SWITCHING	CHARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 500 \text{ V}, I_D = 2.0 \text{ A},$	_	13	35	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega \text{ (Note 5)}$	_	30	70	
t _{d(off)}	Turn-Off Delay Time		_	25	60	
t _f	Turn-Off Fall Time		_	35	80	
Qg	Total Gate Charge	$V_{DS} = 800 \text{ V}, I_{D} = 2.0 \text{ A},$	_	12	15.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 5)	-	2.5	-	
Q _{gd}	Gate-Drain Charge		-	6.5	-	
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MA	AXIMUM RATINGS	-	-	•	
Is	Maximum Continuous Drain-Source Diode Forward Current		_	-	1.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Fo	rward Current	_	-	6.0	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.6 A	_	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 2.0 A,	_	520	-	ns
Q _{rr}	Reverse Recovery Charge	dl _F /dt = 100 A/μs	_	2.3	_	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product Product parametric performance is indicated in the Electrical Characteristics for the listed test condition performance may not be indicated by the Electrical Characteristics if operated under different conditions.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L = 120 mH, $I_{AS} = 1.6$ A, $V_{DD} = 50$ V, $R_{G} = 25$ Ω , Starting $T_{J} = 25$ °C.
4. $I_{SD} \le 2.0$ A, di/dt ≤ 300 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_{J} = 25$ °C.
5. Essentially independent of operating temperature.

TYPICAL CHARACTERISTICS

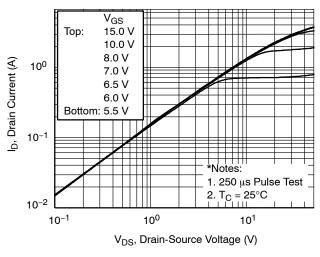


Figure 1. On-Region Characteristics

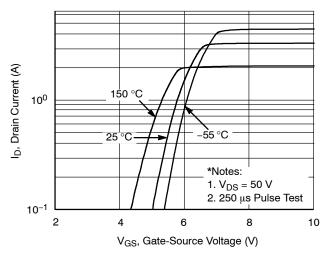


Figure 2. Transfer Characteristics

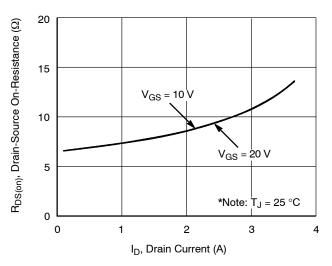


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

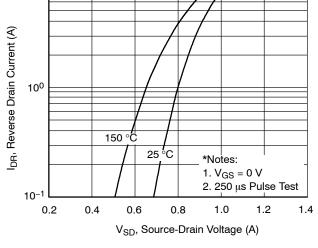


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

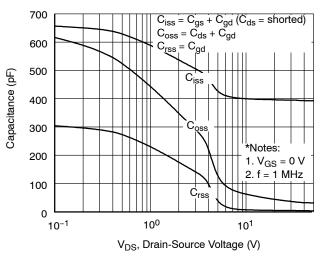


Figure 5. Capacitance Characteristics

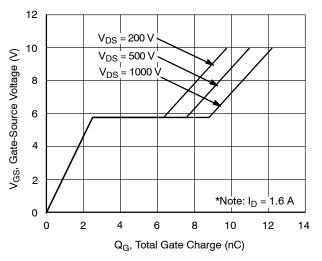
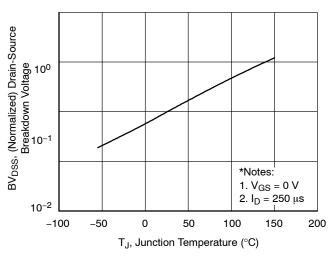


Figure 6. Gate Charge Characteristics

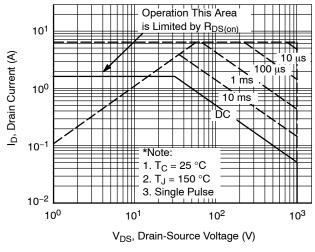
TYPICAL CHARACTERISTICS (CONTINUED)



3.0 R_{DS(ON)}, (Normalized) Drain-Source 2.5 2.0 On-Resistance 1.5 1.0 *Notes: 0.5 1. $V_{GS} = 10 \text{ V}$ $2. I_D = 0.8 A$ 0.0 -100-50 50 100 150 200 T_J, Junction Temperature (°C)

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



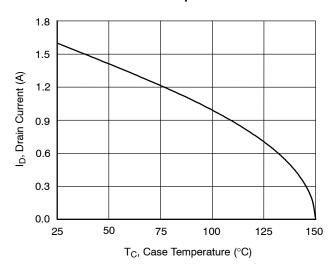


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

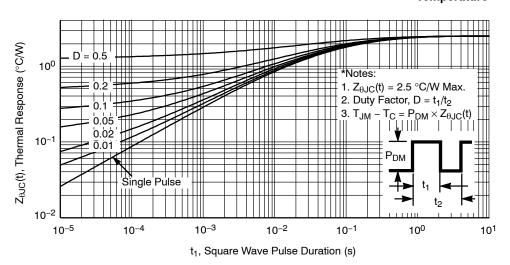


Figure 11. Transient Thermal Response Curve

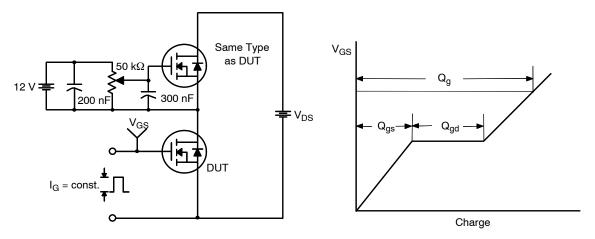


Figure 12. Gate Charge Test Circuit & Waveform

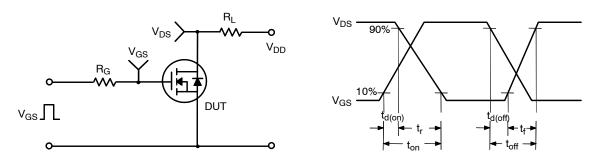


Figure 13. Resistive Switching Test Circuit & Waveforms

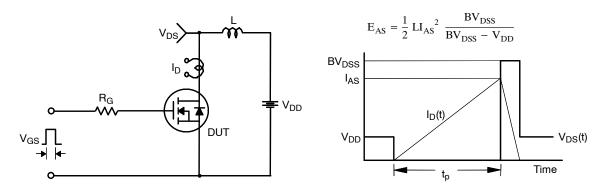


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

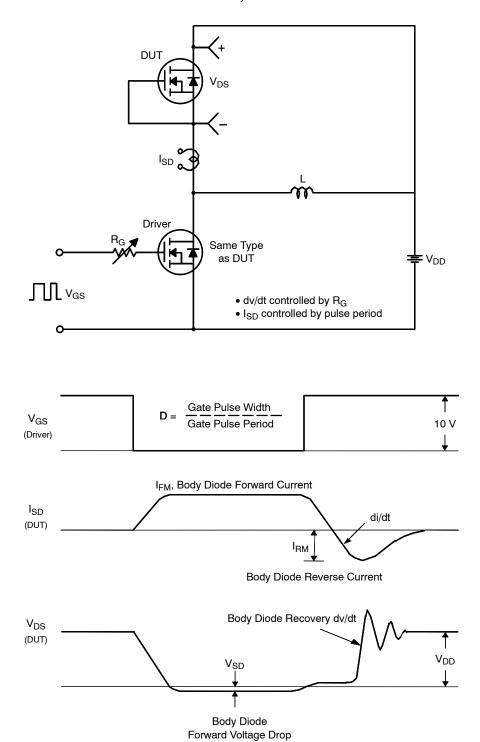


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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REVISION HISTORY

Revision	Description of Changes	Date
5	Added G, D, S description on the 1 st page images (packages) and marked discontinued part number.	10/1/2025

This document has undergone updates prior to the inclusion of this revision history table. The changes tracked here only reflect updates made on the noted approval dates.

THIS PACKAGE CONFORMS TO JEDEC, TO-251,

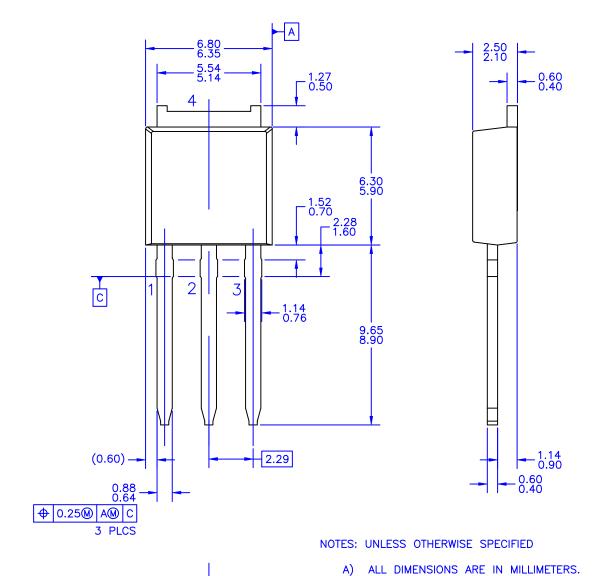
ISSUE C, VARIATION AA, DATED SEP 1988.

DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.



DPAK3 (IPAK) CASE 369AR ISSUE O

DATE 30 SEP 2016



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DESCRIPTION:	DPAK3 (IPAK)		PAGE 1 OF 1

B)

C)

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DPAK3 6.10x6.54x2.29, 4.57P CASE 369AS **ISSUE B**

DATE 20 DEC 2023



- NOTES: UNLESS OTHERWISE SPECIFIED

 A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE F, VARIATION AA.

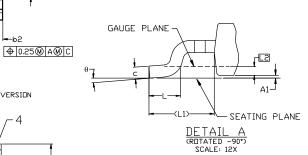
 B) ALL DIMENSIONS ARE IN MILLIMETERS.

 C) DIMENSIONING AND TOLERANCING PER

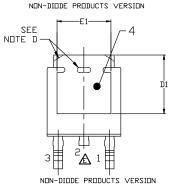
 - D)

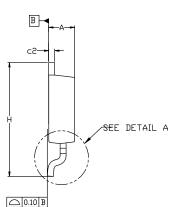
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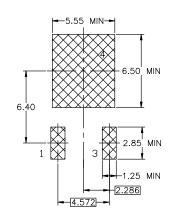
- F)
- DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-2018.
 SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED
 CORNERS OR EDGE PROTRUSION.
 FOR DIGDE PRODUCTS, L4 IS 0.25 MM MAX PLASTIC BODY
 STUB WITHOUT CENTER LEAD.
 DIMENSIONS ARE EXCLUSIVE OF BURRS,
 MOLD FLASH AND TIE BAR EXTRUSIONS.
 LAND PATTERN RECOMMENDATION IS BASED ON IPC7351A STD
 T0228P991X239-3N.



DIM	MILLIMETERS		
DIII	MIN.	N□M.	MAX.
Α	2.18	2.29	2.39
A1	0.00	-	0.127
b	0.64	0.77	0.89
b2	0.76	0.95	1.14
b3	5.21	5.34	5.46
C	0.45	0.53	0.61
c2	0.45	0.52	0.58
D	5.97	6.10	6.22
D1	5.21		
E	6.35	6.54	6.73
E1	4.32		
е	2.286 BSC		
e1	4.5	572 BS	С
Н	9.40	9.91	10.41
L	1.40	1.59	1.78
L1	2.90 REF		
L2	0.51 BSC		
L3	0.89	1.08	1.27
L4			1.02
θ	0°		10°







LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

GENERIC MARKING DIAGRAM*

XXXXXX XXXXXX AYWWZZ

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "=", may or may not be present. Some products may not follow the Generic Marking.

XXXX = Specific Device Code

= Assembly Location Α

Υ

WW = Work Week

77 = Assembly Lot Code

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